

MOSFET

Metal Oxide Semiconductor Field Effect Transistor

OptiMOS[™]

OptiMOS[™] Power-Transistor, 60 V IPA040N06N

Data Sheet

Rev. 2.1 Final





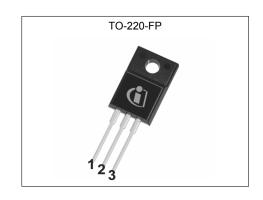
1 **Description**

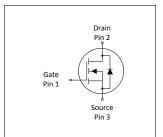
Features

- Optimized for high performance SMPS, e.g. sync. rec.
 100% avalanche tested
- Superior thermal resistance
- N-channel
- Qualified according to JEDEC¹⁾ for target applications
 Pb-free lead plating; RoHS compliant
 Halogen-free according to IEC61249-2-21



i do i i i i i i i i i i i i i i i i i i						
Parameter	Value	Unit				
V _{DS}	60	V				
R _{DS(on),max}	4.0	mΩ				
I _D	69	A				
Qoss	44	nC				
Q _G (0V10V)	38	nC				











Type / Ordering Code	Package	Marking	Related Links
IPA040N06N	PG-TO220-FP	040N06N	-



OptiMOS[™] Power-Transistor, 60 V

IPA040N06N

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2 Maximum ratings at $T_j = 25$ °C, unless otherwise specified

Table 2 Maximum ratings

Danamatan	Oh a l	Values			1114	N	
Parameter	Symbol	Min. Typ.		Max.	Unit	Note / Test Condition	
Continuous drain current	I _D	-	-	69 48	А	V _{GS} =10 V, T _C =25 °C V _{GS} =10 V, T _C =100 °C	
Pulsed drain current ¹⁾	I _{D,pulse}	-	-	276	Α	T _C =25 °C	
Avalanche energy, single pulse ²⁾	E AS	-	-	77	mJ	$I_{\rm D}$ =69 A, $R_{\rm GS}$ =25 Ω	
Gate source voltage	V _{GS}	-20	-	20	V	-	
Power dissipation	P _{tot}	-	-	36	W	<i>T</i> _C =25 °C	
Operating and storage temperature	T _j , T _{stg}	-55	-	175	°C	IEC climatic category; DIN IEC 68-1: 55/175/56	

Thermal characteristics 3

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition	
Parameter	Syllibol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Thermal resistance, junction - case	R _{thJC}	-	3.1	4.2	K/W	-	

Electrical characteristics

Table 4 Static characteristics

Parameter.	0		Values			N	
Parameter	Symbol	Min.	Min. Typ. Max		Unit	Note / Test Condition	
Drain-source breakdown voltage	V _{(BR)DSS}	60	-	-	V	V _{GS} =0 V, I _D =1 mA	
Gate threshold voltage	$V_{\rm GS(th)}$	2.1	2.8	3.3	V	$V_{\rm DS}=V_{\rm GS},\ I_{\rm D}=50\ \mu{\rm A}$	
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	V _{DS} =60 V, V _{GS} =0 V, T _j =25 °C V _{DS} =60 V, V _{GS} =0 V, T _j =125 °C	
Gate-source leakage current	I_{GSS}	-	10	100	nA	V _{GS} =20 V, V _{DS} =0 V	
Drain-source on-state resistance	R _{DS(on)}	-	3.6 4.7	4.0 5.0	mΩ	V _{GS} =10 V, I _D =69 A V _{GS} =6 V, I _D =18 A	
Gate resistance ³⁾	R _G	-	1.3	1.95	Ω	-	
Transconductance	g fs	55	110	-	S	V _{DS} >2 I _D R _{DS(on)max} , I _D =69 A	

See figure 3 for more detailed information
 See figure 13 for more detailed information
 Defined by design. Not subject to production test



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Dynamic characteristics¹⁾ Table 5

Downwater	Cramb al	Values			11:4	Note / Test Condition	
Parameter	Symbol		Тур.	Max.	Unit	Note / Test Condition	
Input capacitance	C _{iss}	-	2700	3375	pF	V _{GS} =0 V, V _{DS} =30 V, f=1 MHz	
Output capacitance	Coss	-	670	838	pF	V _{GS} =0 V, V _{DS} =30 V, f=1 MHz	
Reverse transfer capacitance	C _{rss}	-	28	56	pF	V _{GS} =0 V, V _{DS} =30 V, f=1 MHz	
Turn-on delay time	$t_{\sf d(on)}$	-	14	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =69 A, $R_{\rm G,ext}$ =3 Ω	
Rise time	t _r	-	16	-	ns	V_{DD} =30 V, V_{GS} =10 V, I_{D} =69 A, $R_{\text{G,ext}}$ =3 Ω	
Turn-off delay time	$t_{\sf d(off)}$	-	33	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =69 A, $R_{\rm G,ext}$ =3 Ω	
Fall time	t _f	-	8	-	ns	$V_{\rm DD}$ =30 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =69 A, $R_{\rm G,ext}$ =3 Ω	

Gate charge characteristics²⁾ Table 6

Danamatan	Oh al		Values			Nata / Table Operation	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Gate to source charge	Q _{gs}	-	13	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =69 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge at threshold	$Q_{g(th)}$	-	8	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =69 A, $V_{\rm GS}$ =0 to 10 V	
Gate to drain charge ¹⁾	$Q_{ m gd}$	-	7	9	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =69 A, $V_{\rm GS}$ =0 to 10 V	
Switching charge	Q _{sw}	-	13	-	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =69 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge total	Q_g	-	38	44	nC	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =69 A, $V_{\rm GS}$ =0 to 10 V	
Gate plateau voltage	V _{plateau}	-	4.8	-	V	$V_{\rm DD}$ =30 V, $I_{\rm D}$ =69 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge total, sync. FET	Q _{g(sync)}	-	33	-	nC	V _{DS} =0.1 V, V _{GS} =0 to 10 V	
Output charge ¹⁾	Qoss	-	44	55	nC	V _{DD} =30 V, V _{GS} =0 V	

Table 7 Reverse diode

Danamatan	Comple ed		Values			Nata / Tant Candition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	30	Α	<i>T</i> _C =25 °C	
Diode pulse current	I _{S,pulse}	-	-	276	Α	<i>T</i> _C =25 °C	
Diode forward voltage	V _{SD}	-	0.88	1.2	V	V _{GS} =0 V, I _F =30 A, T _j =25 °C	
Reverse recovery time ¹⁾	t _{rr}	-	33	53	ns	V _R =30 V, I _F =30 A, di _F /dt=100 A/μs	
Reverse recovery charge ¹⁾	Qrr	-	28	-	nC	V _R =30 V, I _F =30 A, di _F /dt=100 A/μs	

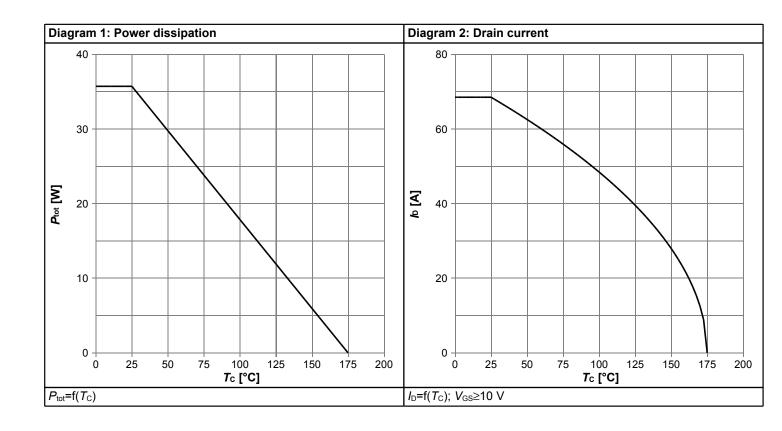
Final Data Sheet

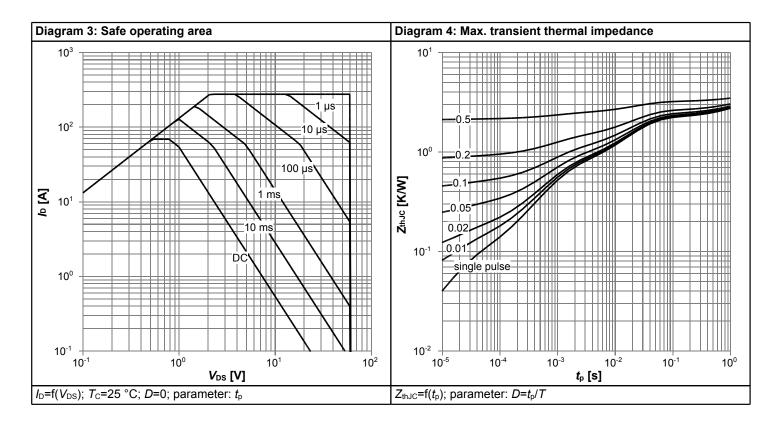
 $^{^{1)}}$ Defined by design. Not subject to production test $^{2)}$ See "Gate charge waveforms" for parameter definition

⁵ Rev. 2.1, 2014-06-19

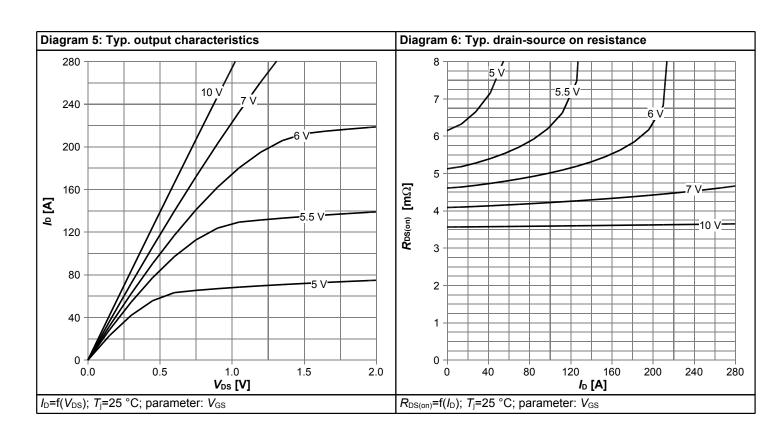


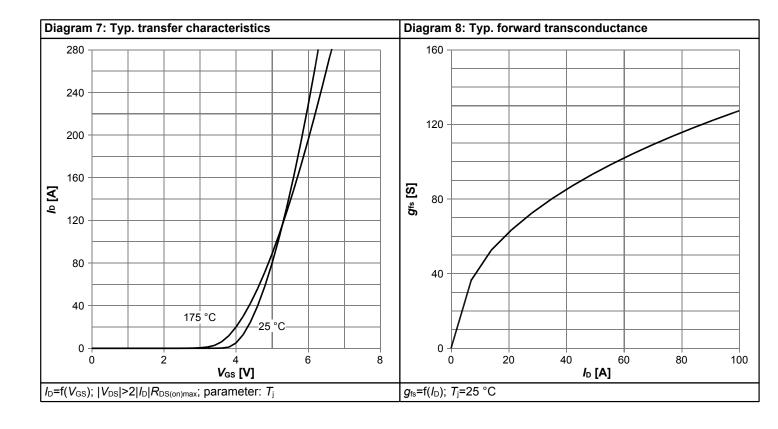
5 Electrical characteristics diagrams



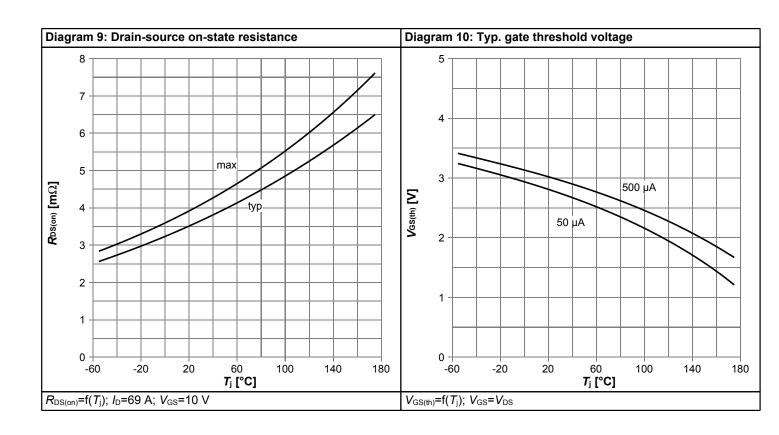


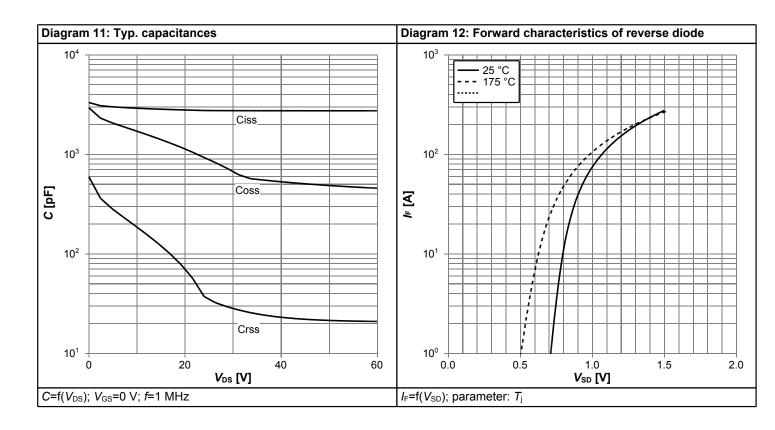




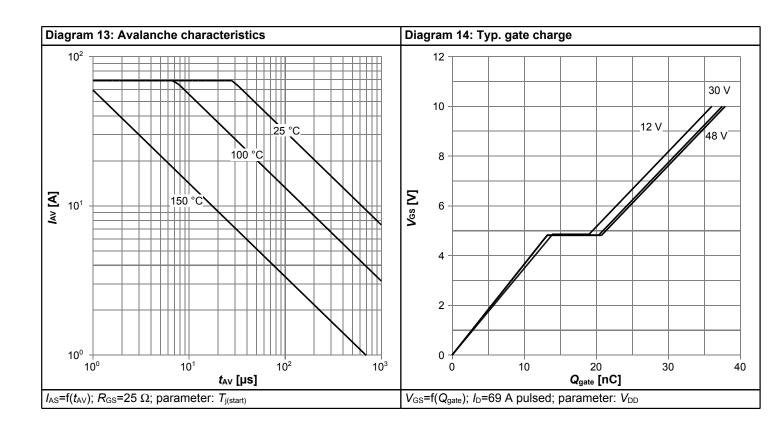


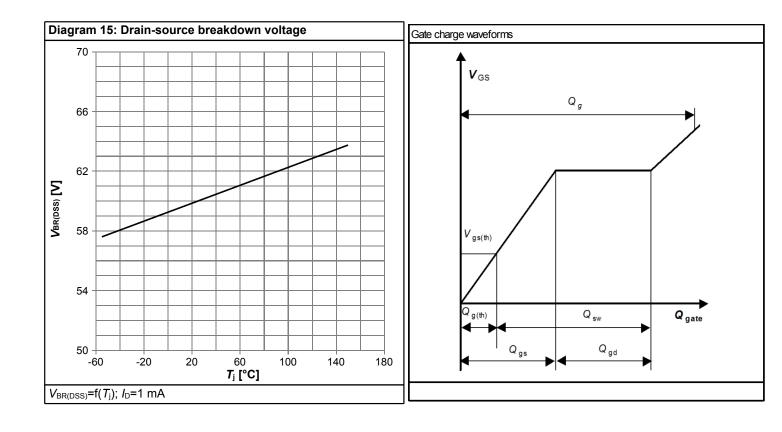






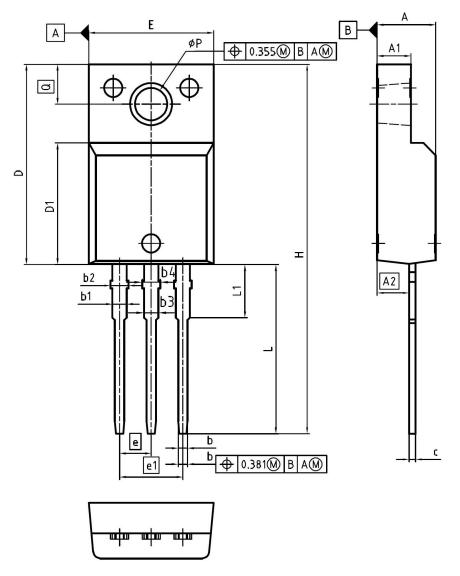








6 Package Outlines



DIM	MILLIMI	ETERS	INCH	IES	
ЫМ	MIN	MAX	MIN	MAX	
Α	4.55	4.85	0.179	0.191	
A1	2.55	2.85	0.100	0.112	
A2	2.42	2.72	0.095	0.107	
b	0.65	0.85	0.026	0.033	
ь1	0.95	1.33	0.037	0.052	
b2	0.95	1.51	0.037	0.059	
b3	0.65	1.33	0.026	0.052	
b4	0.65	1.51	0.026	0.059	
С	0.40	0.63	0.016	0.025	
D	15.85	16.15	0.624	0.636	
D1	9.53	9.83	0.375	0.387	
E	10.35	10.65	0.407	0.419	
е	2.5	54	0.100		
e1	5.0)8	0.200		
N	;	3	(3	
Н	29.45	29.75	1.159	1.171	
L	13.45	13.75	0.530	0.541	
L1	3.15	3.45	0.124	0.136	
øΡ	2.95	3.20	0.116	0.126	
Q	3.15	3.50	0.124	0.138	

DOCUME Z8B000	
SCALE	0
0 2.5 hh.	2.5 5mm
EUROPEAN P	ROJECTION
	
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REVISI 03	

Figure 1 Outline PG-TO220-FP, dimensions in mm/inches



OptiMOS[™] Power-Transistor, 60 V

IPA040N06N

Revision History

IPA040N06N

Revision: 2014-06-19, Rev. 2.1

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.1	2014-06-19	Rev.2.1

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